

10/053,818

SD

10/08/04

Claims 1 through 5 are cancelled

6. (previously presented) An IC test apparatus comprising:
- a. a rigid support member having an opening therein, thereby defining a peripheral edge around the opening,
  - b. a polymer membrane attached to the rigid support member and having a center portion covering the opening,
  - c. a probe contact array on the center portion of the polymer membrane,
  - d. a wafer platform,
  - e. means for depressing the center portion of the polymer membrane toward the wafer platform,
  - f. at least one reference circuit component attached to the polymer membrane and located adjacent to the probe contact array, and
  - g. ~~interconnection means~~ address runners interconnecting the reference circuit component and the probe contact array.

Art Unit: 2829

7. (previously presented) The apparatus of claim 6 wherein the reference circuit component comprises an LC circuit.

8. (previously presented) The apparatus of claim 7 wherein the reference circuit component comprises ~~is part of~~ a passive IC chip.

9. (previously presented) The apparatus of claim 6 wherein the reference circuit component comprises ~~is part of~~ a digital test circuit.

Claims 10 through 19 are cancelled